AE60P04S-Q1

P-Channel Enhancement Mode MOSFET

Product Summary

$V_{(BR)DSS}$	$R_{DS(on)MAX}$	I_D
-40V	7.5mΩ@-10V	-60A
	10.5mΩ@-4.5V	

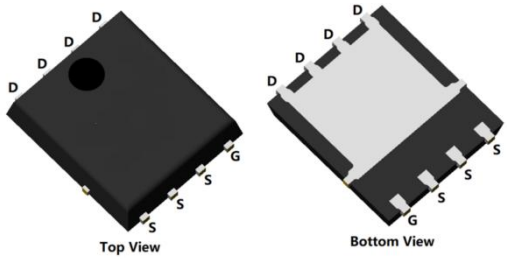
Feature

- Split gate trench MOSFET technology
- Low $R_{DS(on)}$ & FOM
- Excellent stability and uniformity
- Suffix "-Q1" for AEC-Q101

Application

- Power management
- Portable equipment

Package



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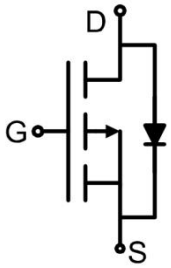
Circuit diagram



Marking

AE60P04S-Q1

P-Channel Enhancement Mode MOSFET

Absolute maximum ratings (T_A=25℃ unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DS}	-40	V
Gate-Source Voltage	V_{GS}	±25	V
Continuous Drain Current (T_C=25℃)	I_D	-60	A
Continuous Drain Current (T_C=100℃)	I_D(100℃)	-38	A
Pulsed Drain Current[1)]	I_{DM}	-240	A
Power Dissipation[3)]	P_D	2.5	W
Thermal Resistance,Junction-to-Ambient[4)]	$R_{\theta JA}$	50	℃/W
Single pulse avalanche energy[2)]	E_{AS}	400	mJ
Junction Temperature	T_J	150	℃
Storage Temperature	T_{STG}	-55 ~ +150	℃

Electrical characteristics (T_J=25 ℃, unless otherwise noted)

Parameter	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Static Characteristics						
Drain-source breakdown voltage	$V_{(BR)DSS}$	V_{GS}= 0V, I_D =-250μA	-40			V
Zero gate voltage drain current	I_{DSS}	V_{DS} =-40V,V_{GS} = 0V			-1	μA
Gate-body leakage current	I_{GSS}	V_{GS} =±25V, V_{DS} = 0V			±100	nA
Gate threshold voltage	$V_{GS(th)}$	V_{DS} =V_{GS}, I_D =-250μA	-1.2	-1.7	-2.5	V
Drain-source on-resistance	$R_{DS(on)}$	V_{GS} =-10V, I_D =-30A		5.5	7.5	mΩ
		V_{GS} =-10V, I_D =-20A		5.5	7.5	mΩ
		V_{GS} =-4.5V, I_D =-20A		7.5	10.5	mΩ
Dynamic characteristics[5)]						
Input Capacitance	C_{iss}	V_{DS} =-20,V_{GS} =0V,f =1MHz		4600		pF
Output Capacitance	C_{oss}			490		
Reverse Transfer Capacitance	C_{rss}			470		
Total Gate Charge	Q_g	V_{DS} =-20V,V_{GS} =-10V, I_D =-30A		99		nC
Gate-Source Charge	Q_{gs}			14		
Gate-Drain Charge	Q_{gd}			22		
Turn-on delay time	$t_{d(on)}$	V_{DD}=-20V,V_{GS}=-10V, I_D=-30A,R_{GEN}=3Ω		11		nS
Turn-on rise time	t_r			52		
Turn-off delay time	$t_{d(off)}$			331		
Turn-off fall time	t_f			185		
Source-Drain Diode characteristics						
Diode Forward Current	I_S				-60	A
Diode Forward voltage	V_{SD}	V_{GS} =0V, I_S=-30A			-1.2	V
Reverse Recovery Time	t_{rr}	I_F =-30A , di/dt = 100A/μs		16		nS
Reverse Recovery Charge	Q_{rr}			16		nC

Notes:

1) Repetitive rating; pulse width limited by max. junction temperature.

2) T_J=25℃, V_{DD}=-30V, V_G=-10V, R_G=25Ω, L=2mH, IAS=-20A.

3) P_d is based on max. junction temperature, using junction-case and junction-ambient thermal resistance.

4) The value of $R_{\theta JA}$ is measured with the device mounted on the minimum recommend pad size, in the still air environment with T_A =25℃. The maximum allowed junction temperature of 150℃. The value in any given application depends on the user's specific board design.

5) Guaranteed by design, not subject to production testing.

Typical Characteristics

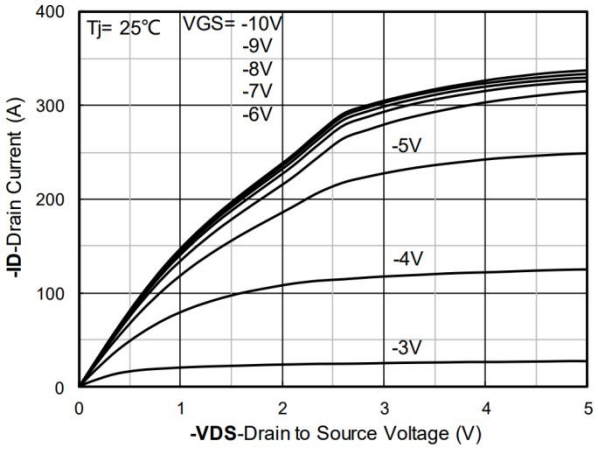


Figure 1. Output Characteristics

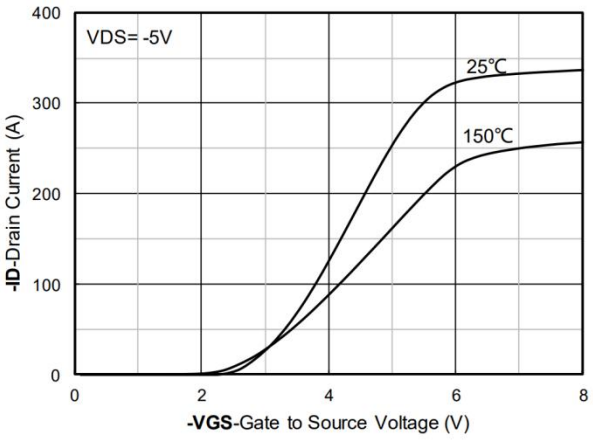


Figure 2. Transfer Characteristics

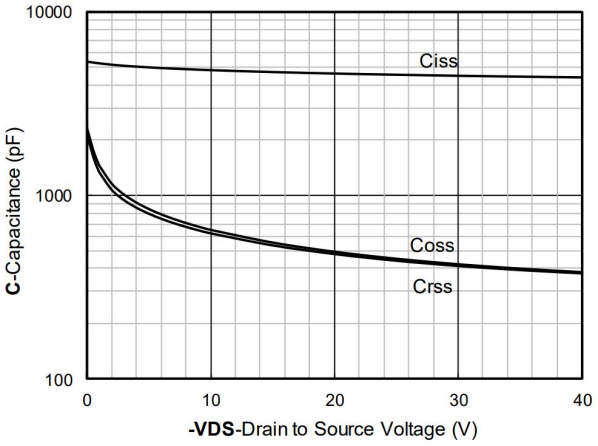


Figure 3. Capacitance Characteristics

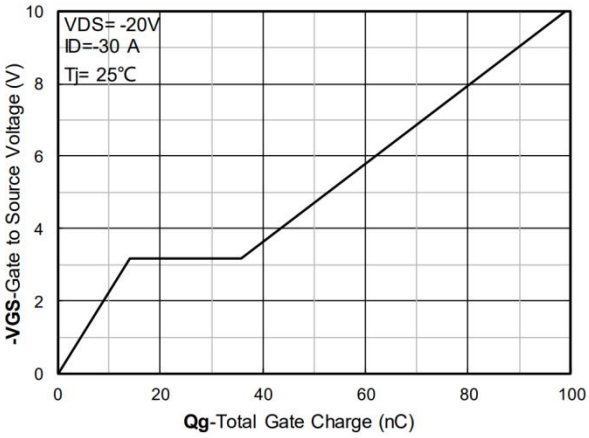


Figure 4. Gate Charge

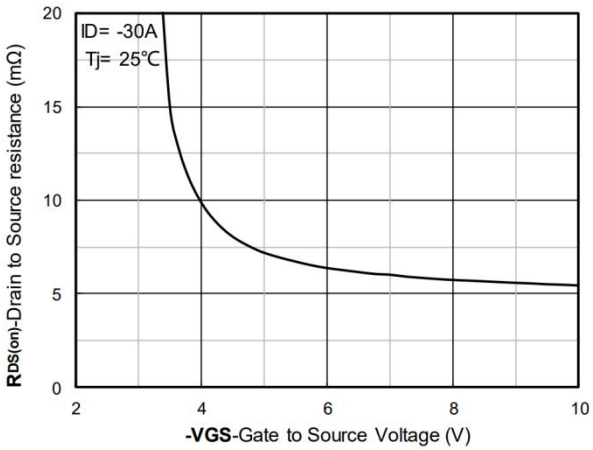


Figure 5. On-Resistance vs Gate to Source Voltage

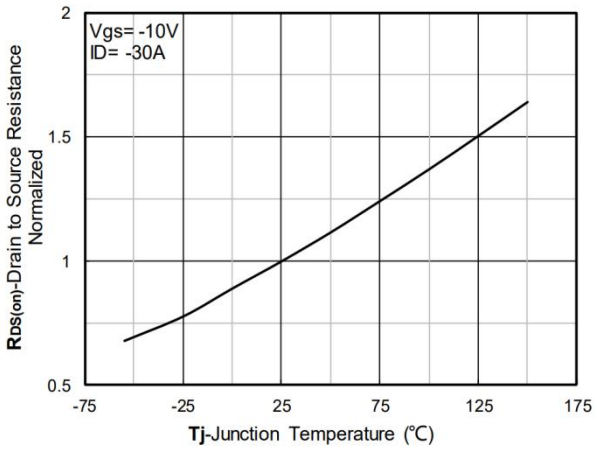


Figure 6. Normalized On-Resistance

Typical Characteristics

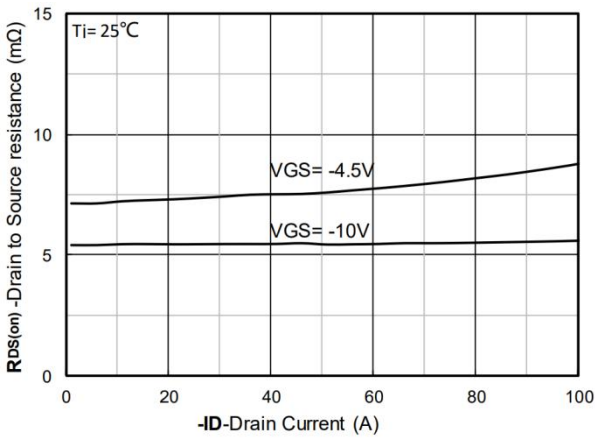


Figure 7. $R_{DS(on)}$ VS Drain Current

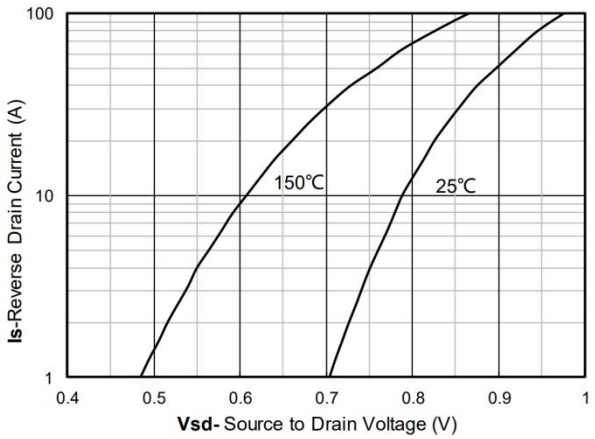


Figure 8. Forward characteristics of reverse diode

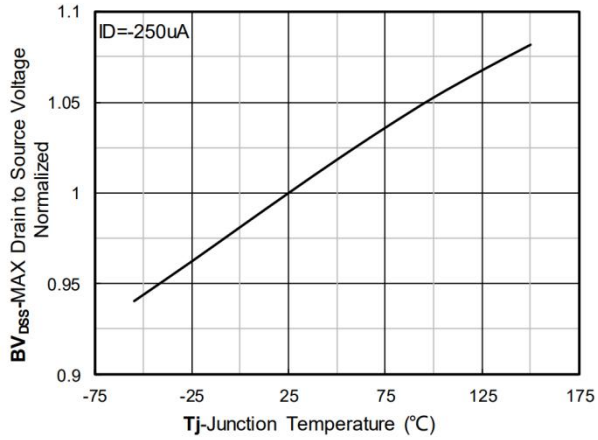


Figure 9. Normalized breakdown voltage

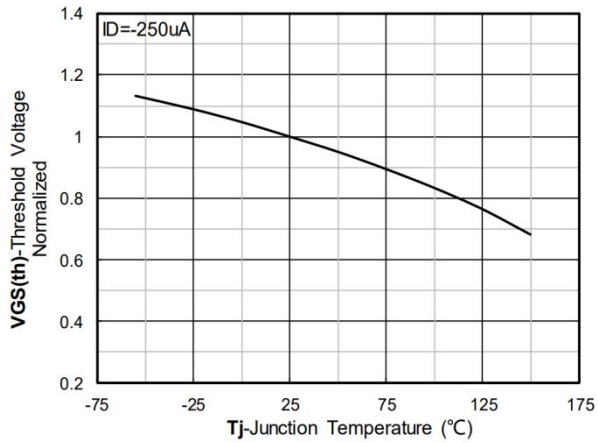


Figure 10. Normalized Threshold voltage

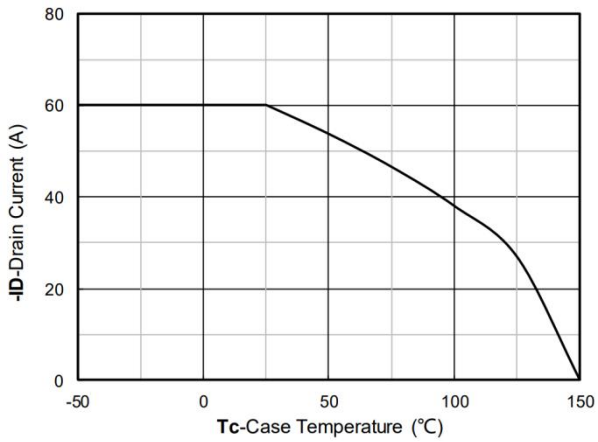


Figure 11. Current dissipation

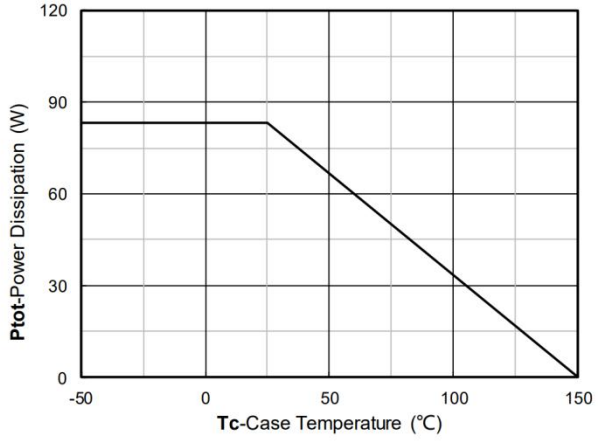


Figure 12. Power dissipation

Typical Characteristics

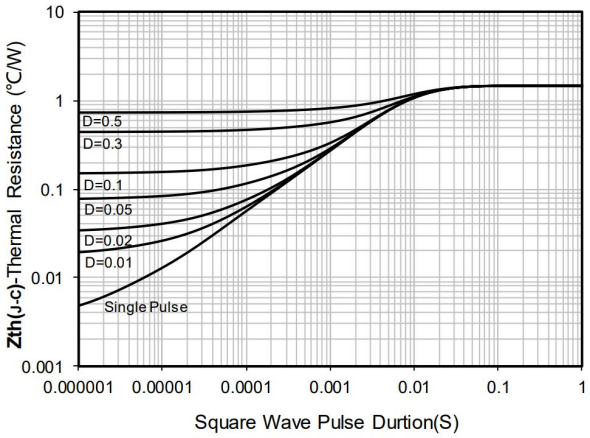


Figure 13. Maximum Transient Thermal Impedance

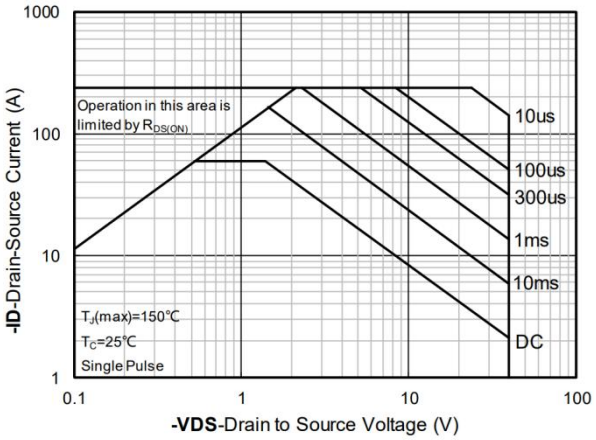
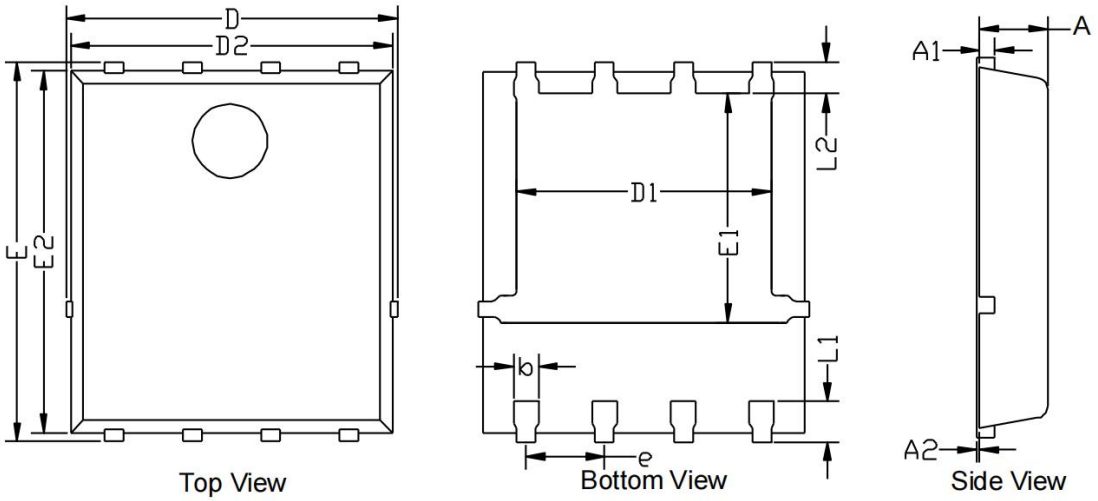


Figure 14. Safe Operation Area

PDFN5*6-8L Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	1.000	1.200	0.039	0.047
A1	0.254 BSC		0.010 BSC	
A2	0.000	0.100	0.000	0.004
D	5.150	5.550	0.203	0.219
E	5.950	6.350	0.234	0.250
D1	3.910	4.320	0.154	0.170
E1	3.520	3.920	0.139	0.154
D2	5.000	5.400	0.197	0.213
E2	5.660	6.060	0.223	0.239
b	0.310	0.510	0.012	0.020
e	1.270 BSC		0.050 BSC	
L1	0.560	0.760	0.022	0.030
L2	0.500 BSC		0.020 BSC	